

8961726 TEXAS INSTR (OPT0)

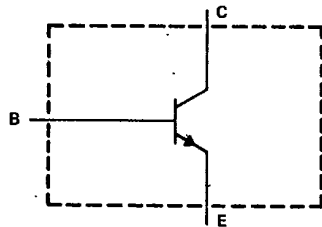
62C 36657 D

BUX80, BUX81
N-P-N SILICON POWER TRANSISTORS

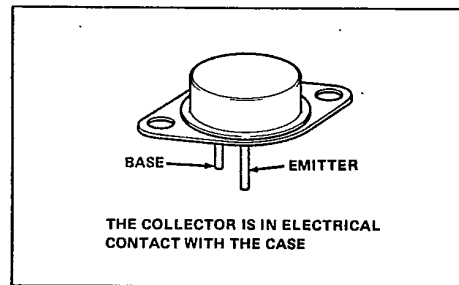
OCTOBER 1982 - REVISED OCTOBER 1984

- 150 W at 25°C Case Temperature
- 10 A Continuous Collector Current
- 15 A Peak Collector Current
- Series Features High-Voltage and Peak Current Ratings, Low Saturation Voltages, and a High Degree of Electrical Robustness
- Designed for Switching-Mode Power Supplies, CRT Scanning, Inverters, and Other Industrial Applications Where Rapid Switching of Inductive Loads is Necessary

device schematic



TO-3 PACKAGE



absolute maximum ratings at 25°C case temperature (unless otherwise noted)

	BUX80	BUX81
Collector-emitter voltage ($V_{BE} = 0$)	800 V	1000 V
Collector-emitter voltage ($R_{BE} = 10 \Omega$)	500 V	500 V
Collector-emitter voltage ($I_B = 0$)	400 V	450 V
Continuous collector current	10 A	
Peak collector current (see Note 1)	15 A	
Continuous base current	4 A	
Peak base current (see Note 1)	6 A	
Continuous device dissipation ($T_C = 25^\circ\text{C}$)	150 W	
Operating junction temperature	-65°C to 200 °C	

NOTE 1: These values apply for $t_W \leq 2$ ms, duty cycle $\leq 10\%$.

BD, BDW, BDX, BU, BUX, BUY Devices

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BUX80, BUX81
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electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	BUX80			BUX81			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	
$V_{CEO(sus)}$	$I_C = 0.1 \text{ A}$, $L = 25 \text{ mH}$, See Note 3	400			450			V
$V_{CER(sus)}$	$I_C = 0.1 \text{ A}$, $L = 15 \text{ mH}$, $R_{BE} = 50 \Omega$, See Note 2	500			500			V
I_{CES}	$V_{CE} = 800 \text{ V}$, $V_{BE} = 0$			1				mA
	$V_{CE} = 800 \text{ V}$, $V_{BE} = 0$, $T_C = 125^\circ\text{C}$			3				
	$V_{CE} = 1000 \text{ V}$, $V_{BE} = 0$						1	
	$V_{CE} = 1000 \text{ V}$, $V_{BE} = 0$, $T_C = 125^\circ\text{C}$						3	
I_{EBO}	$V_{EB} = 10 \text{ V}$, $I_C = 0$			10			10	mA
$V_{CE(sat)}$	$I_C = 5 \text{ A}$, $I_B = 1 \text{ A}$, See Notes 3 and 4			1.5			1.5	V
	$I_C = 8 \text{ A}$, $I_B = 2.5 \text{ A}$, See Notes 3 and 4			3			3	
$V_{BE(sat)}$	$I_C = 5 \text{ A}$, $I_B = 1 \text{ A}$, See Notes 3 and 4			1.4			1.4	V
	$I_C = 8 \text{ A}$, $I_B = 2.5 \text{ A}$, See Notes 3 and 4			1.8			1.8	
f_T	$V_{CE} = 10 \text{ V}$, $I_C = 0.5 \text{ A}$, See Note 5			8			8	MHz
C_{obo}	$V_{CB} = 20 \text{ V}$, $I_E = 0$, $f = 0.1 \text{ MHz}$			105			105	pF

NOTES: 2. Inductive loop switching measurement.

3. These parameters must be measured using pulse techniques, $t_W = 300 \mu\text{s}$, duty cycle = 2%.

4. These parameters are measured with voltage-sensing contacts separated from the current-carrying contacts located within 3.2 mm (0.125 inch) from the device body.

5. To obtain f_T , the $|h_{fe}|$ response is extrapolated at the rate of -6 dB per octave from $f = 1 \text{ MHz}$ to the frequency at which $|h_{fe}| = 1$.

thermal characteristics

PARAMETER	MIN	TYP	MAX	UNIT
$R_{\theta JC}$			1.17	$^\circ\text{C/W}$

resistive-load switching characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{on}	$I_C = 5 \text{ A}$, $V_{CC} = 250 \text{ V}$, $I_{B1} = 1 \text{ A}$, $I_{B2} = -2 \text{ A}$, See Figure 1			0.5	μs
t_g				3.5	μs
t_f				0.8	μs

BD, BDW, BDW, BDX, BU, BUX, BUY Devices

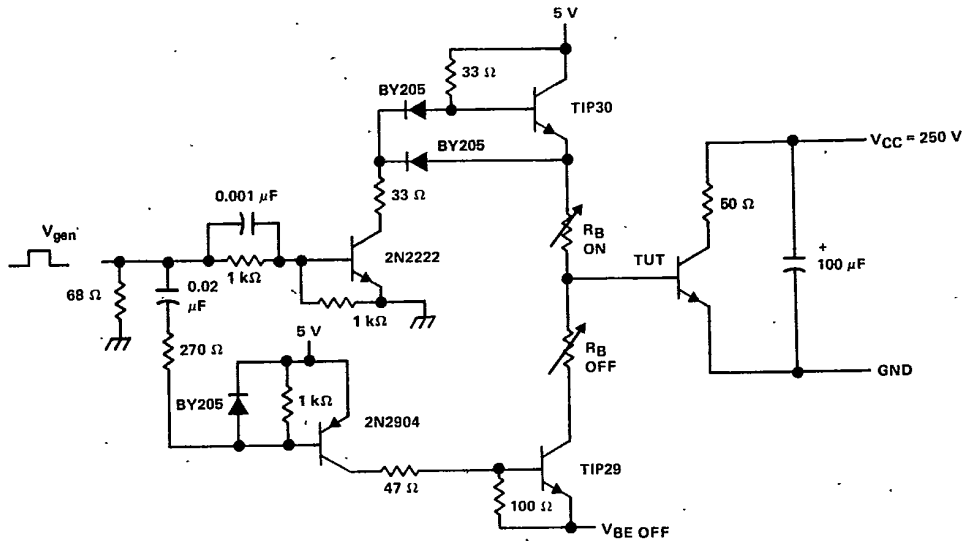
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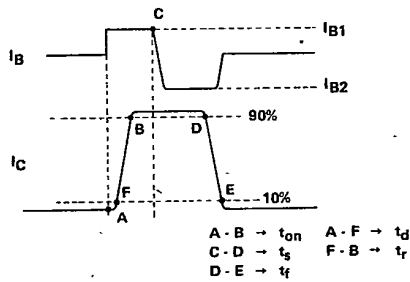
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PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT

- NOTES: A. The V_{gen} waveform is supplied by the following characteristics: $t_r < 15 \text{ ns}$, $t_f < 15 \text{ ns}$, $2_{out} = 50 \Omega$, $t_w = 20 \mu\text{s}$, duty cycle $< 2\%$.
 B. Waveforms are monitored on an oscilloscope with the following characteristics: $t_r < 15 \text{ ns}$, $R_{in} > 10 \text{ M}\Omega$, $C_{in} < 11.5 \text{ pF}$.
 C. Resistors must be noninductive types.



CURRENT WAVEFORMS

FIGURE 1. RESISTIVE-LOAD SWITCHING

BD, BDW, BDW, BU, BUX, BUY Devices

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TYPICAL CHARACTERISTICS

TURN-OFF TIME
vs
COLLECTOR CURRENT

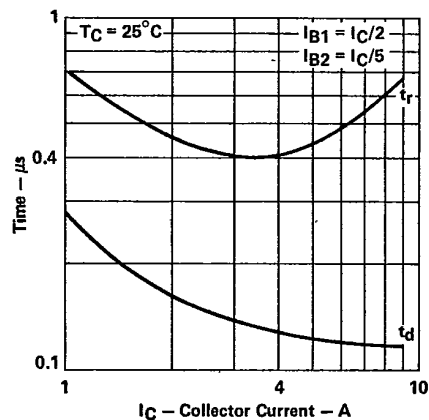


FIGURE 2

TURN-OFF TIME
vs
COLLECTOR CURRENT

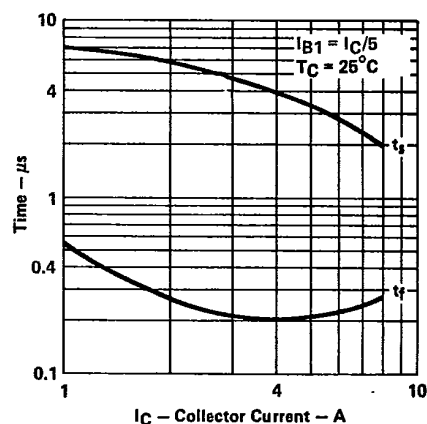


FIGURE 3

COLLECTOR CUTOFF CURRENT
vs
CASE TEMPERATURE

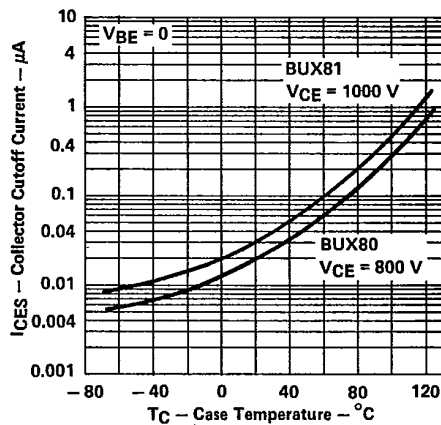


FIGURE 4

FORWARD CURRENT TRANSFER RATIO
vs
COLLECTOR CURRENT

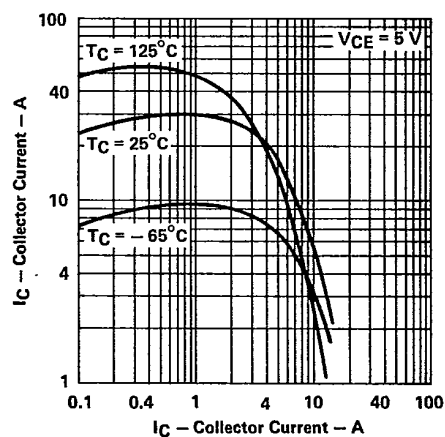


FIGURE 5

BD, BDW, BDX, BU, BUX, BUY Devices

TEXAS
INSTRUMENTS

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TYPICAL CHARACTERISTICS

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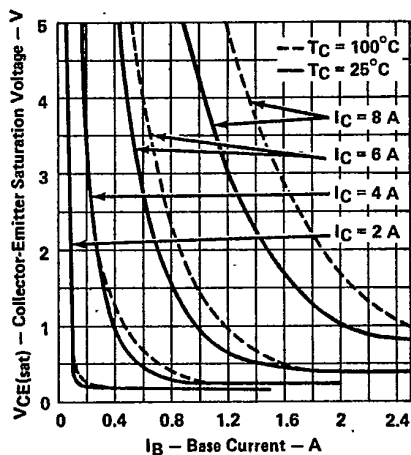
COLLECTOR-EMITTER SATURATION VOLTAGE
vs
BASE CURRENT

FIGURE 6

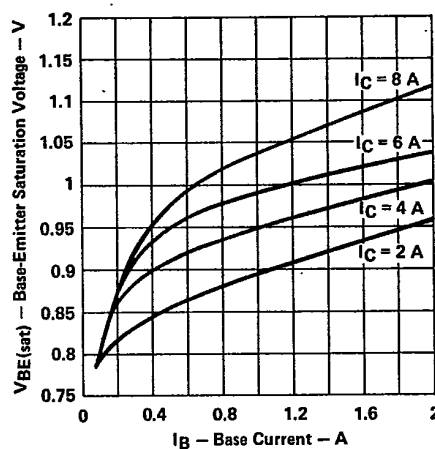
BASE-EMITTER SATURATION VOLTAGE
vs
BASE CURRENT

FIGURE 7

MAXIMUM SAFE OPERATING AREAS

FORWARD-BIAS SAFE OPERATING AREA

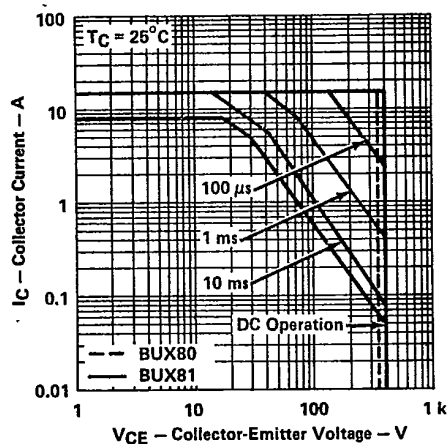


FIGURE 8

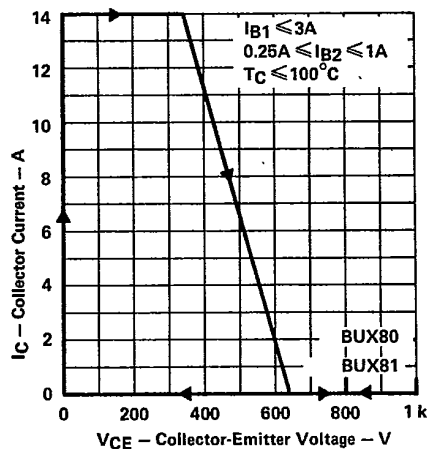
LIMITING CONDITIONS
FOR POWER-DOWN TRANSIENT

FIGURE 9

BD, BDW, BDW, BU, BUX, BUY Devices

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MAXIMUM SAFE OPERATING AREA

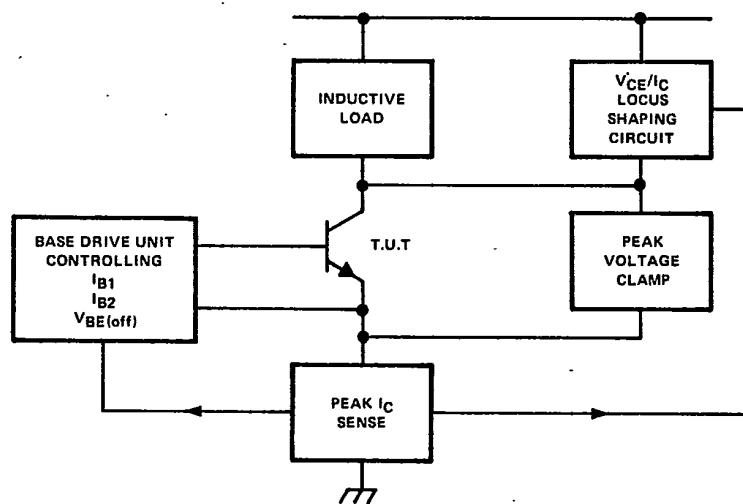


FIGURE 10. TEST CIRCUIT FOR POWER-DOWN TRANSIENT

THERMAL INFORMATION

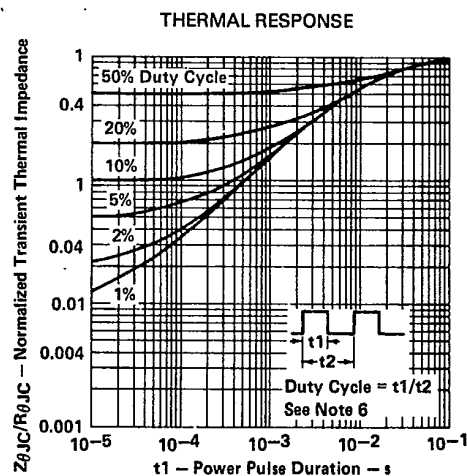


FIGURE 11

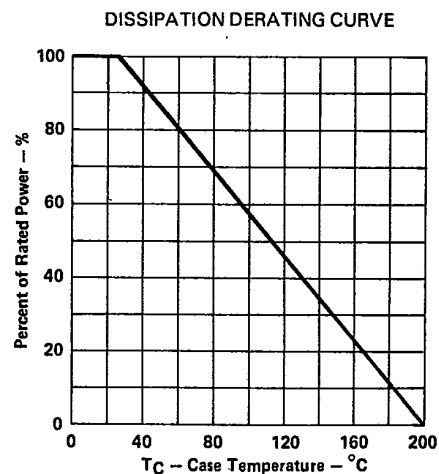


FIGURE 12

NOTE 6: Read time at end of t_1 , $T_J(\max) - T_J(\max) - T_C = P_{D(\text{peak})} \cdot \left(\frac{Z_{\theta JC}}{R_{\theta JC}} \right) \cdot R_{\theta JC}(\max)$.

BD, BDW, BDX, BU, BUX, BUY Devices